

WHAT IS CLAIMED IS:

1. A calibration pattern unit which obtains correction information of an imaging system by imaging at the imaging system, the unit comprising:

5 a calibration pattern in which a predetermined pattern is formed on one of a plurality of three-dimensionally arranged planes and one or more curved surfaces; and

10 a relative position and posture fixing section which fixes relative position and posture between the calibration pattern and the imaging system.

2. A calibration pattern unit which obtains correction information of an imaging system by imaging at the imaging system, the unit comprising:

15 one of a plurality of three-dimensionally arranged planes and one or more curved surfaces; and

20 a calibration pattern in which a predetermined pattern is formed on the one of a plurality of three-dimensionally arranged planes or one or more curved surfaces and in a range where a shape is substantially similar to an object imaged by the imaging system.

25 3. The unit according to claim 2, wherein a ratio between the object imaged by the imaging system and the pattern in the range where the shape is substantially similar in width, height and depth is about 1.0.

4. A calibration pattern unit which obtains correction information of an imaging system by imaging

at the imaging system, the unit comprising:

a calibration pattern in which a predetermined pattern is formed on one of a plurality of three-dimensionally arranged planes and one or more curved surfaces; and

an imaging area instruction section configured to instruct an area to be imaged when the calibration pattern is imaged.

5. The unit according to claim 4, wherein

10 the unit comprises a plurality of imaging systems which enable imaging of the object from a plurality of view points, and

the imaging area instruction section corresponds to only one of the plurality of imaging systems.

15 6. The unit according to claim 4, wherein

the unit comprises a plurality of imaging systems which enable imaging of the object from a plurality of view points, and

the imaging area instruction section corresponds to the plurality of imaging systems.

20 7. A calibration pattern unit which obtains correction information of an imaging system by imaging at the imaging system, the unit comprising:

25 a calibration pattern in which a predetermined pattern is formed on one of a plurality of three-dimensionally arranged planes and one or more curved surfaces; and

an imaging posture instruction section configured to instruct a posture of the imaging system with respect to the calibration pattern.

8. The unit according to claim 7, wherein
5 the unit comprises a plurality of imaging systems which enable imaging of the object from a plurality of view points, and

the imaging posture instruction section corresponds to only one of the plurality of imaging
10 systems.

9. The unit according to claim 7, wherein
the unit comprises a plurality of imaging systems which enable imaging of the object from a plurality of view points, and

15 the imaging posture instruction section corresponds to the plurality of imaging systems.

10. The unit according to claim 7, wherein the imaging posture instruction section is a bar-shaped instruction member extended in an optical axis direction of the imaging system when the imaging system
20 carries out imaging for calibration.